

Semiconductor devices — Time Dependent Dielectric Breakdown (TDDB) test for gate dielectric films

ICS 31.080.01

National foreword

This British Standard is the UK implementation of EN 62374:2007. It is identical to IEC 62374:2007.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

Compliance with a British Standard cannot confer immunity from legal obligations.

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